

New Jersey Semi-Conductor Products, Inc.

20 STERN AVE.
SPRINGFIELD, NEW JERSEY 07081
U.S.A.

TELEPHONE: (973) 376-2922
(212) 227-6005
FAX: (973) 376-8960

MD7003, F (SILICON)

MD7003A, AF

MD7003B

MQ7003

MULTIPLE SILICON ANNULAR TRANSISTORS

...designed for use as high-gain, low-noise differential amplifiers, front end detectors, and temperature compensation applications.

- Low Collector-Emitter Saturation Voltage – $V_{CE(sat)} = 0.25$ Vdc (Typ) @ $I_C = 10$ mAdc
- DC Current Gain Specified @ $100 \mu\text{A}/\text{mA}$ and $10 \text{ mA}/\text{mA}$
- High Current-Gain-Bandwidth Product – $f_T = 300$ MHz (Typ) @ $I_C = 5.0$ mAdc

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	V_{CEO}	40	Vdc
Collector-Base Voltage	V_{CB}	50	Vdc
Emitter-Base Voltage	V_{EB}	5.0	Vdc
Collector Current – Continuous	I_C	50	mAdc
		One Die	All Die Equal Power
Total Power Dissipation @ $T_A = 25^\circ\text{C}$	P_D		mW
MD7003,A,B		550	600
MD7003F,AF		350	400
MQ7003		400	600
Derate above 25°C			mW/ $^\circ\text{C}$
MD7003,A,B		3.14	3.42
MD7003F,AF		2.0	2.28
MQ7003		2.28	3.42
Total Power Dissipation @ $T_C = 25^\circ\text{C}$	P_D		Watts
MD7003,A,B		1.4	2.0
MD7003F,AF		0.7	1.4
MQ7003		0.7	2.8
Derate above 25°C			mW/ $^\circ\text{C}$
MD7003,A,B		8.0	11.4
MD7003F,AF		4.0	8.0
MQ7003		4.0	16
Operating and Storage Junction Temperature Range	T_J, T_{stg}	-65 to +200	$^\circ\text{C}$

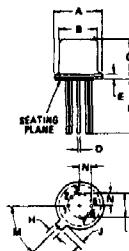
THERMAL CHARACTERISTICS

Characteristic	Symbol	One Die	All Die Equal Power	Unit
Thermal Resistance, Junction to Ambient	$R_{\theta JA(1)}$			$^\circ\text{C}/\text{W}$
MD7003,A,B		319	292	
MD7003F,AF		500	438	
MQ7003		438	292	
Thermal Resistance, Junction to Case	$R_{\theta JC}$			$^\circ\text{C}/\text{W}$
MD7003,A,B		125	87.5	
MD7003F,AF		250	125	
MQ7003		250	62.6	
Coupling Factor		Junction to Ambient	Junction to Case	%
MD7003,A,B		83	40	
MD7003F,AF		75	0	
MQ7003 (Q1-Q2) (Q1-Q3 or Q1-Q4)		67	0	
		55	0	

(1) $R_{\theta JA}$ is measured with the device soldered into a typical printed circuit board.

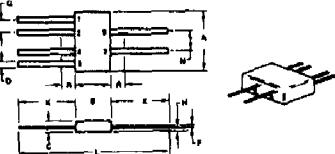
PNP SILICON DUAL TRANSISTORS

MD7003,A,B



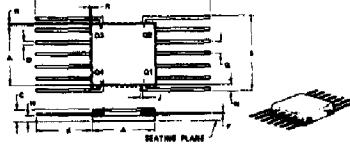
DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	8.51	9.49	0.335	0.370
B	7.75	8.51	0.305	0.335
C	3.81	4.70	0.150	0.185
D	0.41	0.53	0.016	0.021
E	5.08 BSC	5.20 BSC		
F	0.71	0.86	0.028	0.034
G	0.74	1.14	0.029	0.045
H	12.70	—	0.500	—
I	45° BSC	45° BSC		
J	2.54 BSC	3.00 BSC		
K	2.54 BSC	3.00 BSC		

MD7003F,AF



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	8.10	9.36	0.314	0.380
B	7.97	4.06	0.311	0.160
C	6.76	7.31	0.265	0.286
D	0.36	0.48	0.014	0.019
E	0.00	0.15	0.003	0.006
F	0.00	0.27 BSC	0.008	0.050
G	—	0.88	—	0.035
H	3.81	—	0.150	—
I	2.54 BSC	3.00 BSC		
J	—	1.27	—	0.050

MQ7003



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	8.10	6.89	0.314	0.275
B	7.76	2.02	0.305	0.080
C	3.75	0.48	0.150	0.019
D	0.00	0.15	0.003	0.006
E	0.00	0.27 BSC	0.008	0.050
F	0.13	0.89	0.005	0.035
G	—	0.38	—	0.015
H	6.35	—	0.250	—
I	10.00	—	0.740	—
J	0.25	—	0.010	—
K	0.38	—	0.015	—
L	7.62	0.38	0.300	0.330

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Quality Semi-Conductors

MD7003,A,AF,B,F, MQ7003 (continued)

THERMAL COUPLING AND EFFECTIVE THERMAL RESISTANCE

In multiple chip devices, coupling of heat between die occurs. The junction temperature can be calculated as follows:	Assuming equal thermal resistance for each die, equation (1) simplifies to
(1) $\Delta T_{J1} = R_{\theta 1} P_{D1} + R_{\theta 2} K_{\theta 2} P_{D2} + R_{\theta 3} K_{\theta 3} P_{D3} + R_{\theta 4} K_{\theta 4} P_{D4}$	(3) $\Delta T_{J1} = R_{\theta 1} (P_{D1} + K_{\theta 2} P_{D2} + K_{\theta 3} P_{D3} + K_{\theta 4} P_{D4})$
Where ΔT_{J1} is the change in junction temperature of die 1 $R_{\theta 1}$ thru 4 is the thermal resistance of die 1 through 4 P_{D1} thru 4 is the power dissipation in die 1 through 4 $K_{\theta 2}$ thru 4 is the thermal coupling between die 1 and die 2 through 4.	For the conditions where $P_{D1} = P_{D2} = P_{D3} = P_{D4}$; $P_{DT} = 4P_D$ equation (3) can be further simplified and by substituting into equation (2) results in
An effective package thermal resistance can be defined as follows:	(4) $R_{\theta(EFF)} = R_{\theta 1} (1 + K_{\theta 2} + K_{\theta 3} + K_{\theta 4}) / 4$
(2) $R_{\theta(EFF)} = \Delta T_{J1}/P_{DT}$ Where: P_{DT} is the total package power dissipation.	Values for the coupling factors when either the case or the ambient is used as a reference are given in the table on page 1. If significant power is to be dissipated in two die, die at the opposite ends of the package should be used so that lowest possible junction temperatures will result.

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ C$ unless otherwise noted.)

Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS					
Collector-Emitter Breakdown Voltage (1) ($I_C = 10 \mu A_{dc}$, $I_B = 0$)	V_{CEO}	40	—	—	Vdc
Collector-Base Breakdown Voltage ($I_C = 10 \mu A_{dc}$, $I_B = 0$)	V_{CBO}	50	—	—	Vdc
Emitter-Base Breakdown Voltage ($I_E = 10 \mu A_{dc}$, $I_C = 0$)	V_{EBO}	5.0	—	—	Vdc
Collector Cutoff Current ($V_{CB} = 30$ Vdc, $I_E = 0$)	I_{CBO}	—	—	100	nAdc
ON CHARACTERISTICS					
DC Current Gain (1) ($I_C = 100 \mu A_{dc}$, $V_{CE} = 10$ Vdc) ($I_C = 10 \text{ mA}_{dc}$, $V_{CE} = 10$ Vdc)	h_{FE}	40 50	350 350	—	—
Collector-Emitter Saturation Voltage ($I_C = 10 \text{ mA}_{dc}$, $I_B = 1.0 \text{ mA}_{dc}$)	$V_{CE(sat)}$	—	0.25	0.35	Vdc
Base-Emitter Saturation Voltage ($I_C = 10 \text{ mA}_{dc}$, $I_B = 1.0 \text{ mA}_{dc}$)	$V_{BE(sat)}$	—	0.6	1.0	Vdc
DYNAMIC CHARACTERISTICS					
Current-Gain-Bandwidth Product ($I_C = 5.0 \text{ mA}_{dc}$, $V_{CE} = 20$ Vdc, $f = 100$ MHz)	f_T	200	300	—	MHz
Output Capacitance ($V_{CB} = 10$ Vdc, $I_B = 0$, $f = 100$ kHz)	C_{ob}	—	3.0	6.0	pF
Input Capacitance ($V_{BE} = 2.0$ Vdc, $I_C = 0$, $f = 100$ kHz)	C_{ib}	—	2.0	8.0	pF
Noise Figure ($I_C = 100 \mu A_{dc}$, $V_{CE} = 10$ Vdc, $R_S = 3.0$ k Ohms, $f = 10$ Hz to 15.7 kHz)	NF	—	2.0	—	dB
MATCHING CHARACTERISTICS					
DC Current Gain Ratio (2) ($I_C = 100 \mu A_{dc}$, $V_{CE} = 10$ Vdc)	h_{FE1}/h_{FE2}	0.76 0.85	—	1.0 1.0	—
Base-Emitter Voltage Differential ($I_C = 100 \mu A_{dc}$, $V_{CE} = 10$ Vdc)	$ V_{BE1}-V_{BE2} $	—	—	25 15	mV

(1) Pulse Test: Pulse Width $\leq 300 \mu s$, Duty Cycle $\leq 2.0\%$.

(2) The lowest h_{FE} reading is taken as h_{FE1} for this ratio.